FISCHERSCOPE® X-RAY XDAL® 237

X-ray fluorescence spectrometer with a programmable X/Y-stage and Z-axis for automated measurements of thin coatings and for materials analysis.

















FISCHERSCOPE X-RAY

Description

The FISCHERSCOPE®-X-RAY XDAL®237 is a universally applicable energy-dispersive x-ray spectrometer. It constitutes the next step in the development of the proven FISCHERSCOPE X-RAY XDAL. Like its predecessor, it is particularly well suited for non-destructive measurements of very thin coatings and for analyses in automated measurement applications.

To create ideal excitation conditions for every measurement, the XDAL 237 features electrically changeable apertures and primary filters. The modern silicon PIN detector achieves a high analysis accuracy and a good detection sensitivity. The XDAL 237 x-ray spectrometer has an excellent long-term stability, which is reflected in a significantly reduced calibration effort, among other things.

Using the fundamental parameter method, coating systems as well as solid and liquid samples can be analyzed standard-free. It is possible to detect up to 24 elements in the range from aluminum (13) to uranium (92) simultaneously.

The XDAL 237 is predestined for measuring and analyzing very thin coatings, even with very complex compositions or small concentrations. With its fast, programmable X/Y-stage, it is the fitting measuring instrument for automated measurements in quality assurance and production monitoring.

Typical areas of application are:

- Analysis of thin or very thin coatings,
 e.g., gold and palladium coatings of ≤ 0.1 µm
- Measurement of functional coatings in the electronics and semiconductor industries
- Determination of complex multi-coating systems
- Automated measurements, e.g., in quality control
- Determination of the lead content in solder

Design

The FISCHERSCOPE X-RAY XDAL 237 is designed as a user-friendly bench-top instrument. It is equipped with a high-precision, programmable X/Y-stage and an electrically driven Z-axis and is thus ideally suited for automated measurements. The sample stage moves out automatically into the loading position, when the protective hood is opened. A laser pointer serves as a positioning aid and supports the quick alignment of the sample to be measured.

A high-resolution color video camera with powerful magnification simplifies the precise determination of the measurement locations and visualizes the running measurement procedure. Fine adjustments can be made directly at the instrument manually or using a joystick - or from the PC using a mouse and the keyboard. The entire operation, the evaluation of the measurement as well as the clear presentation of the measurement data is done on a PC using the powerful and user-friendly WinFTM® Software.

XDAL spectrometers are fully protected instruments with type approval according to the German regulations "Deutsche Röntgenverordnung-RöV".

General Specifications

Intended use Energy dispersive x-ray fluorescence spectrometer (EDXRF) to determine thin

coatings, small structures, traces and alloys

Element range Aluminum Al (13) to Uranium U (92) – up to 24 elements simultaneously

Design Bench-top unit with hood opening upwards

X/Y-stage and Z-axis electrically driven and programmable

Motor-driven exchangeable apertures and filters

Video camera and laser pointer for orienting the sample

Measuring direction From top to bottom

X-ray source

X-ray source Micro focus tube with beryllium window

High voltage Adjustable 30 kV, 40 kV, 50 kV

Apertures (collimators): 4x changeable: Ø 0.1 mm; Ø 0.3 mm; Ø 0.6 mm; slot 0.5 mm x 0.15 mm

(others on request)

Primary filter 3x changeable. (Standard equipment: Nickel, Aluminum, free)

Measurement spot Depending on the measuring distance and on the aperture; the actual measurement

spot size is shown in the video image.

Smallest measurement spot: approx. Ø 0.15 mm.

Measuring distance 0 ... 80 mm, in the non-calibrated range using the patented DCM method

e.g., for measurements in recesses 0 ... 20 mm, in the calibrated range using the patented DCM method

X-ray detection

X-ray detector Silicon PIN detector with peltier cooling

Energy resolution ≤ 180 eV (fwhm at Mn-Kα)

Sample orientation

Video microscope High-resolution CCD color camera for optical monitoring of the measurement

location along the primary beam axis Manual focusing and auto-focus

Crosshairs with a calibrated scale (ruler) and spot-indicator Adjustable LED illumination of the measurement location Laser pointer to support accurate sample placement

Zoom factor up to 180x (Optical: 20x .. 45x; Digital: 1x, 2x, 3x, 4x)

Sample stage Fast, electric motor driven, programmable X/Y-stage

Maximum travel X/Y-axis: 255 mm x 235 mm; Z-axis: 140 mm

Max. travel speed X/Y 80 mm/s

Repeatability precision $X/Y/Z \leq 0.01 \text{ mm (unidirectional)}$

Usable sample placement area Width x depth: 300 mm x 350 mm

Max. sample mass 5 kg, with reduced approach travel precision 20 kg

Max. sample height 140 mm

Line voltage, line frequency AC 115 V or AC 230 V 50 / 60 Hz Power consumption Max. 120 W (without evaluation PC)

IP40 Protection class

Dimensions

Exterior dimensions Width x depth x height [mm]: 570 x 760 x 650

Weight Approx. 120 kg

Interior dimensions measurement

chamber

Width x depth x height [mm]: 460 x 495 x 146

Environmental Conditions

10°C - 40°C / 50°F - 104°F Temperature: Operation Temperature: Storage/Transport 0°C - 50°C / 32°F - 122°F Humidity of ambient air ≤ 95 %, non-condensing

Evaluation unit

Computer PC system with extension cards

Fischer WinFTM® Software

Standards

CE conformity EN 61010

DIN ISO 3497 and ASTM B 568 X-ray standards

Approval Fully protected instrument with type approval according to the German regulations

"Deutsche Röntgenverordnung-RöV"

Order

FISCHERSCOPE X-RAY XDAL 237 604-348



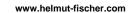
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